

C3

Laboratorio 1



Universidad de Buenos Aires – Exactas
departamento de física

Septiembre 2020

REPASO

Ej. Medida de una longitud x' :

$$(x' \pm \Delta x) \text{ cm} \Rightarrow x' \in (x' - \Delta x, x' + \Delta x)$$

x' (cm)	Δx (cm)	E_r	$E_r\%$	K
2,5	0,1	0,04	4	25
8,3	0,1	0,012	1,2	83
15,0	0,1	0,0067	0,67	120

- * **Errores sistemáticos** (corrimiento de cero, calibración)
- * **Errores causales** (observador, instrumentos,...)

Como definir un rango de incerteza para cada medición directa?

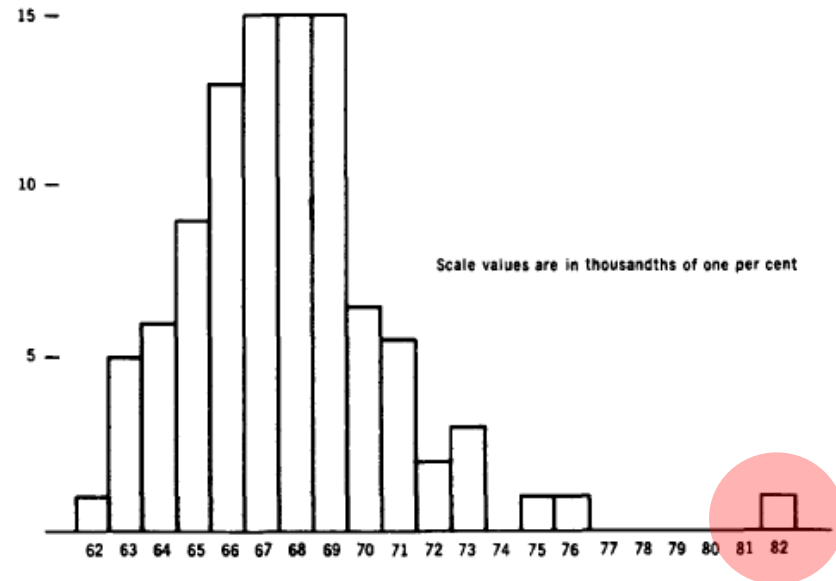
- * Resolución de un instrumento
- * Estadística

Errores casuales => Estadística. N mediciones

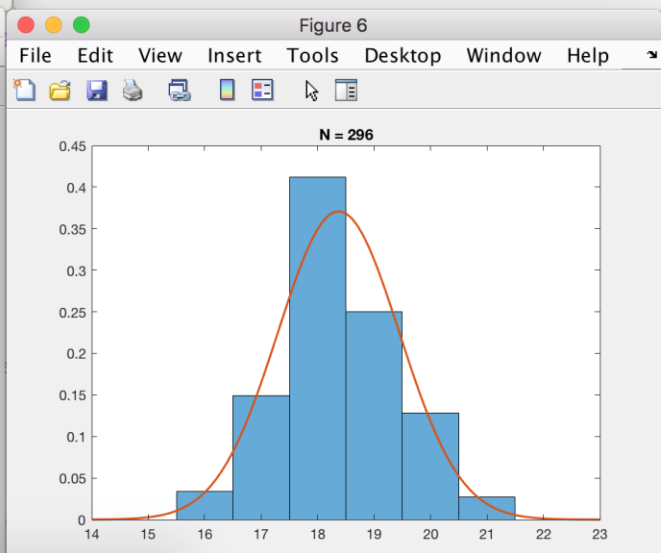
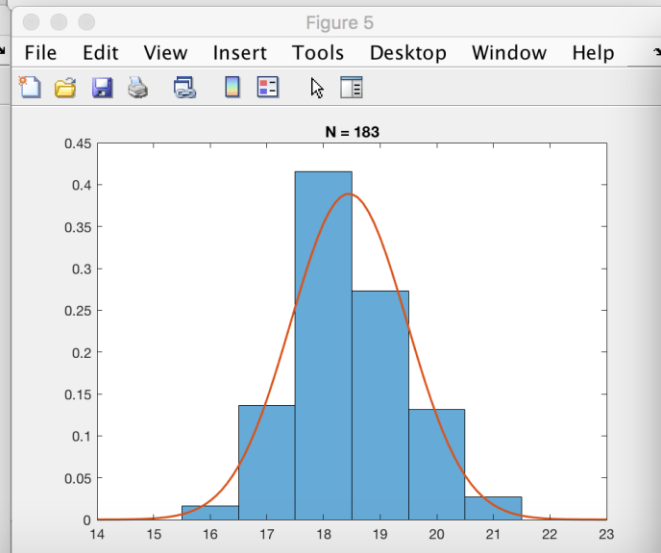
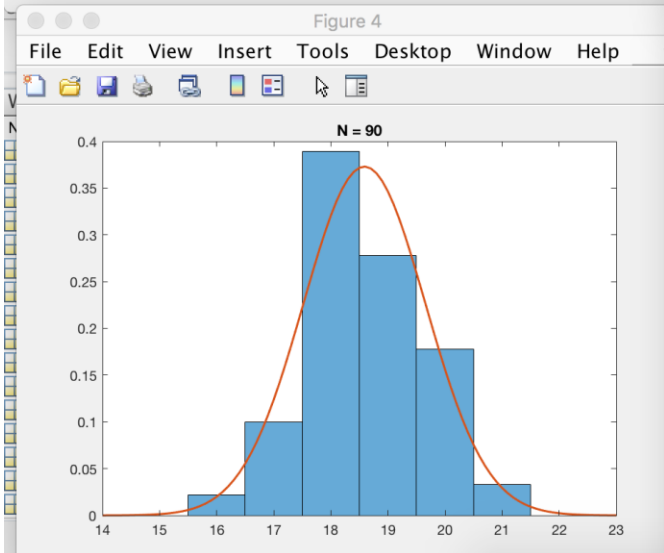
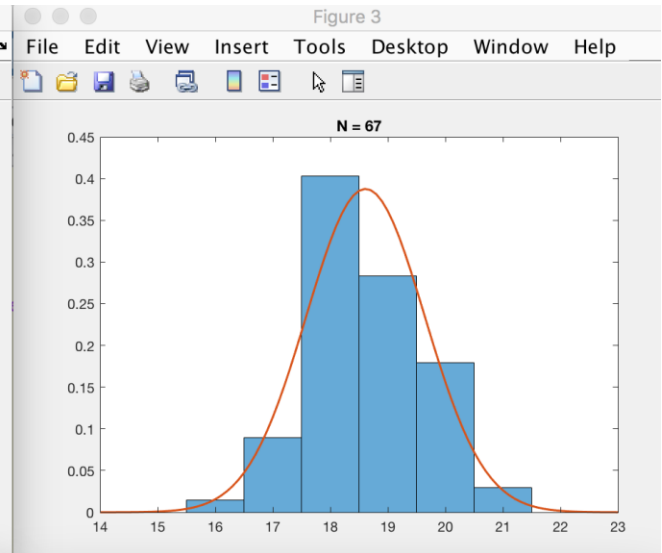
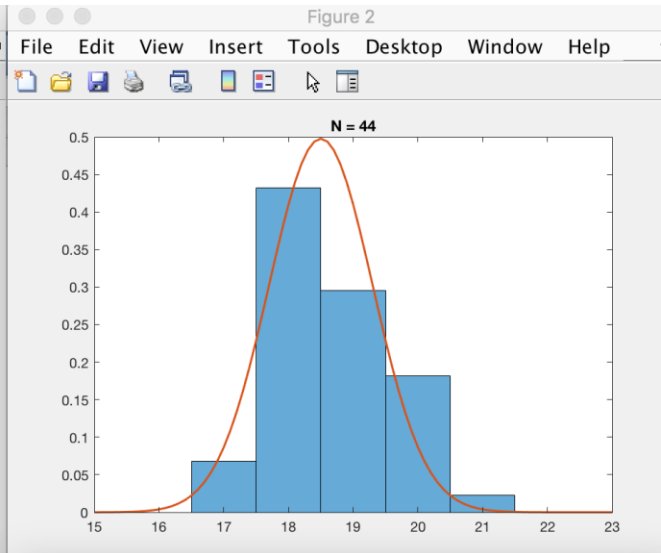
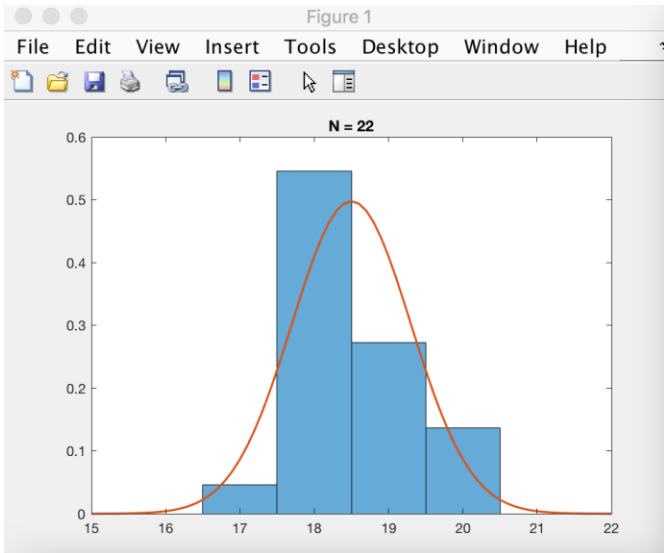
Espesor de una hoja de papel, N= 95

thickness in mm.			
.0757	.0762	.0769	.0746
.0808	.0793	.0781	.0821
.0811	.0772	.0770	.0756
.0655	.0683	.0714	.0746
.0741	.0710	.0748	.0711
.0756	.0772	.0776	.0759
.0775	.0785	.0760	.0761
.0747	.0765	.0735	.0776
.0719	.0762	.0802	.0713
.0734	.0833	.0833	.0783
.0755	.0740	.0714	.0743
.0788	.0817	.0794	.0766
.0731	.0716	.0726	.0714
.0833	.0794	.0783	.0788
.0767	.0775	.0765	.0793
.0787	.0798	.0864	.0817
.0784	.0799	.0789	.0802
.0784	.0820	.0796	.0818
.0830	.0796	.0778	.0767
.0741	.0680	.0733	.0723
.0759	.0766	.0772	.0466*
.0810	.0812	.0789	.0776
.0777	.0759	.0795	.0790
.0784	.0786	.0797	.0859

Contenido de magnesio en caños N=100



Como elegir N



Ejemplos

Figure 2. Histogram for 95 measurements of paper thickness

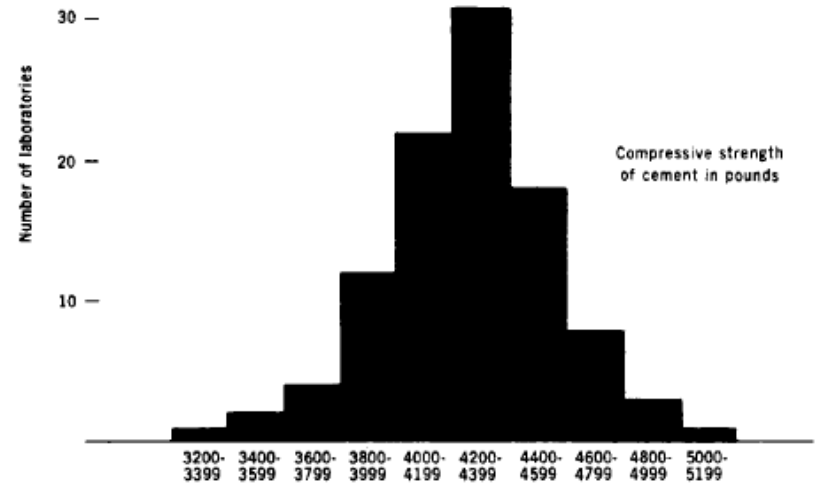
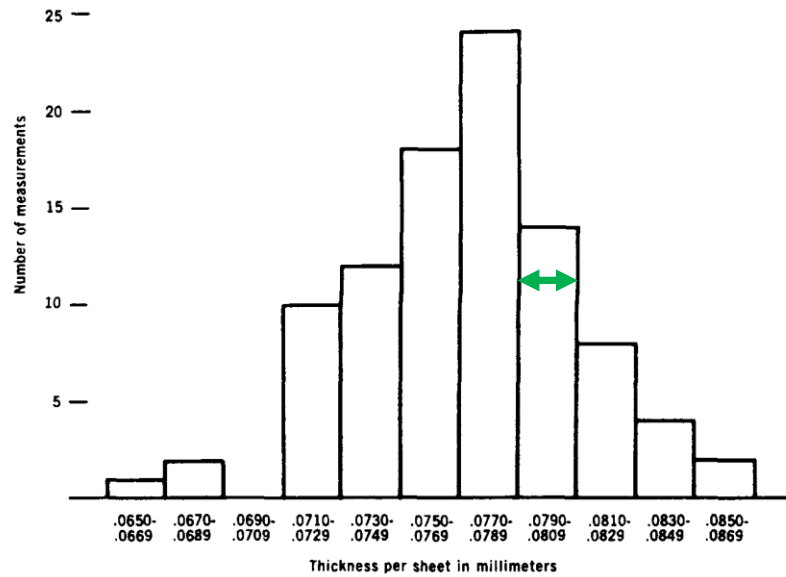
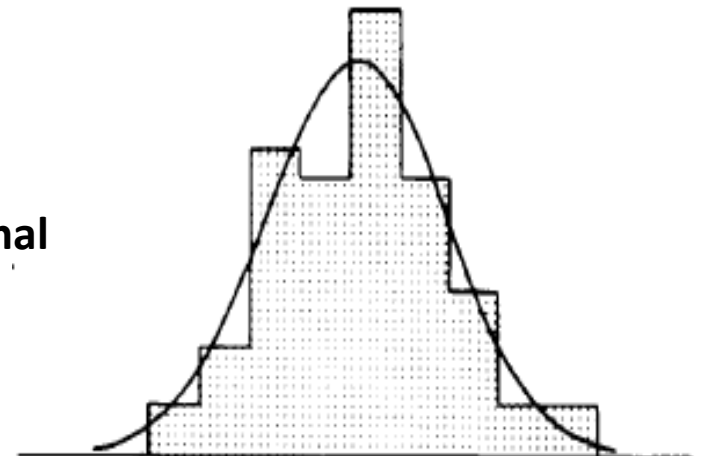


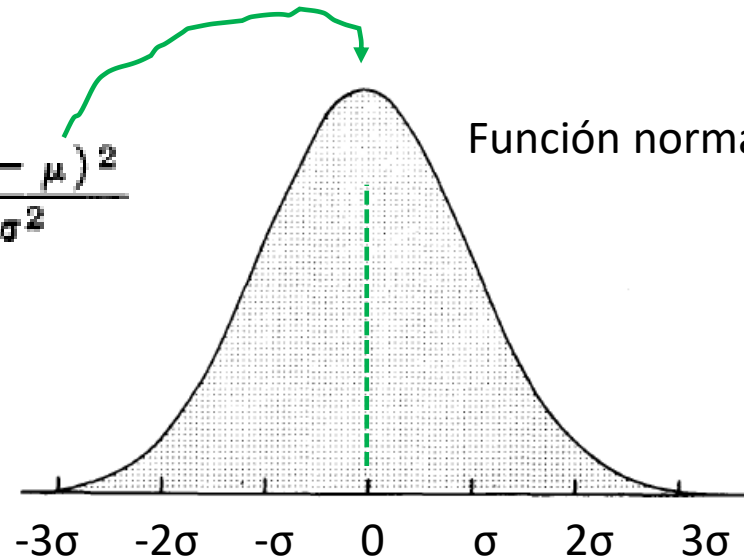
Figure 6. Histogram for cement tests reported by 102 laboratories.

Se describe con una función *Gaussiana* o normal



$$y = \frac{1}{\sigma \sqrt{2\pi}} e^{-\frac{(x - \mu)^2}{2\sigma^2}}$$

Función normal

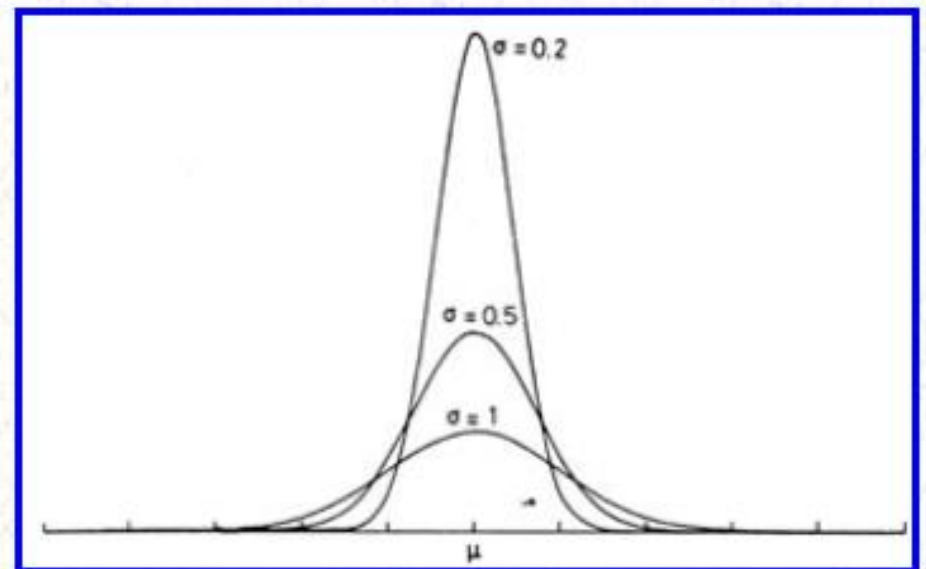


- * Distribución simétrica
- * Limites $x \rightarrow +\infty$, $x \rightarrow -\infty$

Parámetros: μ y σ

Ancho a mitad de altura

$$\text{FWHM} = 2\sigma\sqrt{2\ln 2} = 2.35\sigma.$$

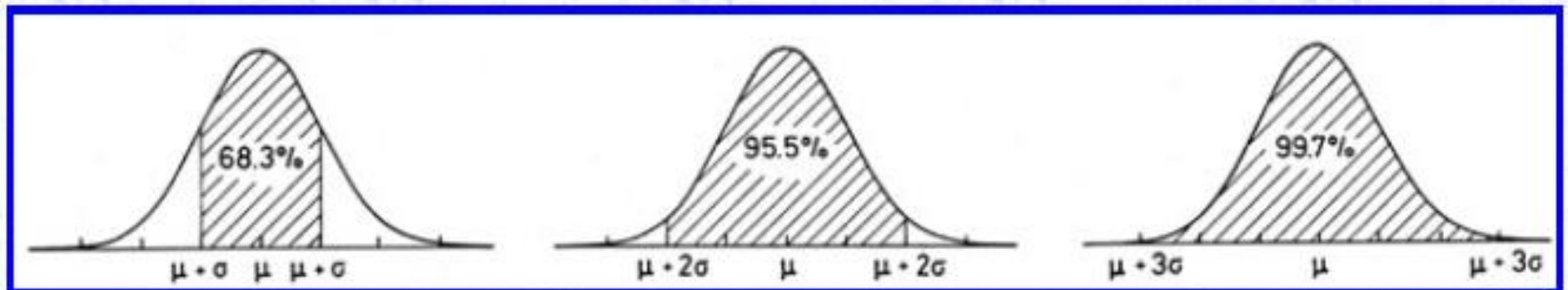


$$y = \frac{1}{\sigma \sqrt{2\pi}} e^{-\frac{(x - \mu)^2}{2\sigma^2}}$$

$$P(x_1 \leq x \leq x_2) = \int_{x_1}^{x_2} P(x) dx$$

$$\int P(x) dx = 1$$

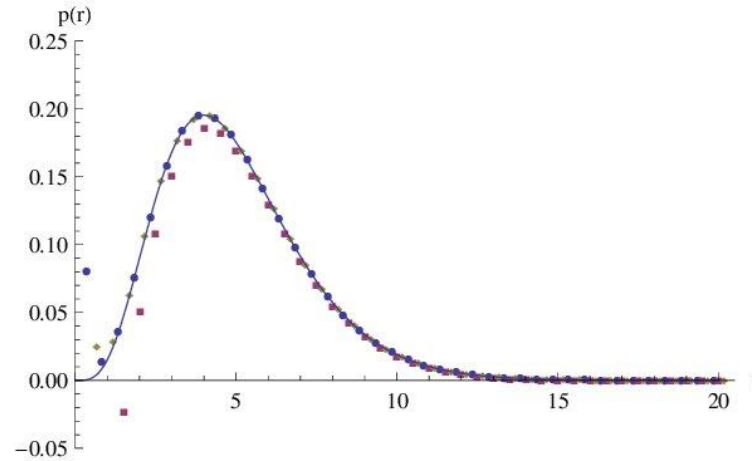
Como calculo el numero de cuentas por intervalo?



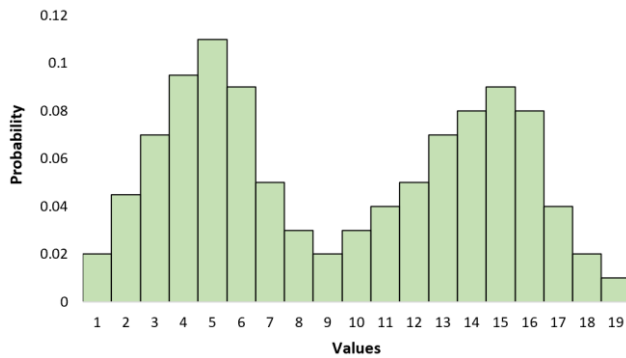
Otras distribuciones

Poisson

$$P(X = x) = \frac{\lambda^x e^{-\lambda}}{x!}$$

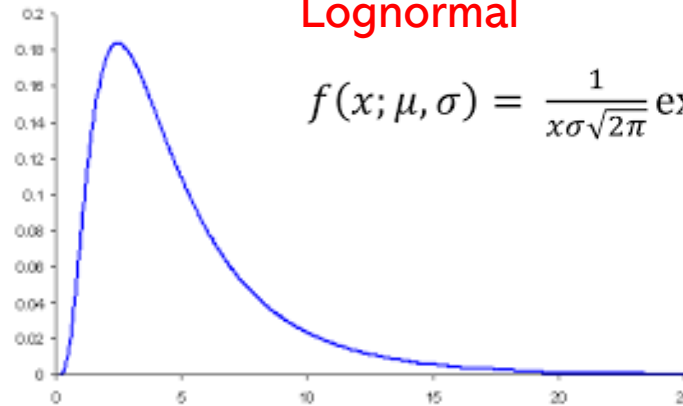


Bimodal



Lognormal

$$f(x; \mu, \sigma) = \frac{1}{x\sigma\sqrt{2\pi}} \exp\left(-\frac{(\ln x - \mu)^2}{2\sigma^2}\right)$$



Practica I

Objetivos: Determinar el **intervalo de incerteza** en una medición. Análisis de la **distribución** de N valores de la medición de una magnitud - estadística

A: Medida de N discos “idénticos”

- Información sobre la imagen: tomada por un microscopio de fuerza atómica. Resolución lateral: algunos nm (dependiendo microscopio)
- Información sobre los discos: los discos están compuestos de una aleación de Ni₈₀Fe₂₀ y micro-fabricados a partir de una película delgada de este material (espesor: 20nm)

B: Medida de la longitud característica de un cuerpo N veces

Análisis de datos: sobre uso del origen

The screenshot displays the OriginPro 9.1 interface. The main window shows a data table with columns A(X) and B(Y). The 'Statistics on Columns' dialog box is open, showing the 'Perform Descriptive Statistics' description. The 'Recalculate' dropdown is set to 'Manual'. The 'Input Data' section is set to 'Independent Columns', with 'Range 1' containing the data range '[Book1]Sheet1!A'. The 'Quantities to Compute' section has several options checked: Moments, N total, Mean, Standard Deviation, SE of mean, Lower 95% CI of Mean, Upper 95% CI of Mean, Variance, Sum, and Skewness. The 'OK' button is highlighted.

	A(X)	B(Y)
Long Name		
Units		
Comments		
F(x)		
1	2	
2	2,3	
3	2,5	
4	2,3	
5	2,4	
6	2,1	
7	2,3	
8	2,4	
9	2,5	
10	2,1	
11	2,2	
12	2,6	
13	2,4	
14	2,3	
15	2,2	
16	2,2	
17	2,1	
18	2,1	
19	2	
20	2,5	
21	2,5	
22		
23		
24		
25		
26		
27		
28		
29		
30		

Project Explorer (1)

Quick Help

Messages Log

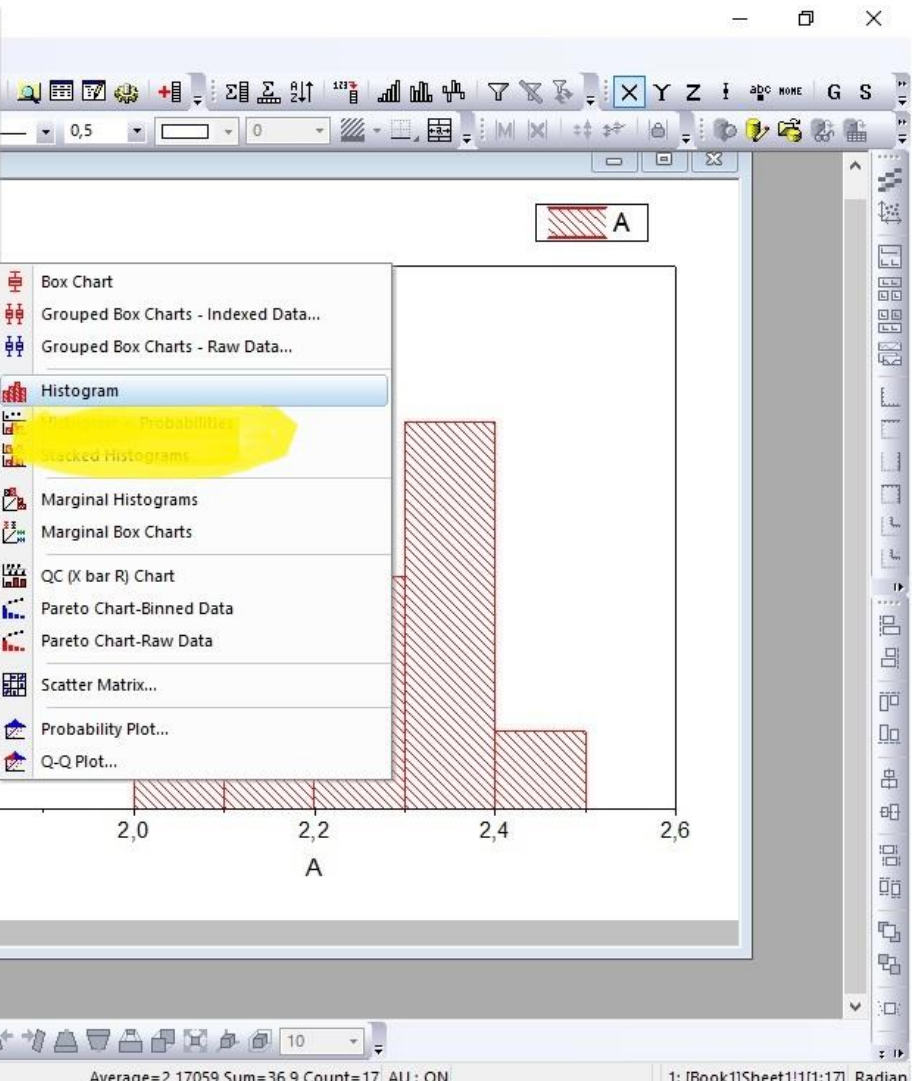
Smart Hint Log (4)

Book1	
Long Name	
Units	
Comments	
F(x)	
9	
10	
11	
12	
13	
14	
15	
16	
17	
18	
19	

Sheet1

- Plot
- Copy Ctrl+X
- Copy Columns to...
- Paste Ctrl+V
- Insert
- Delete
- Clear Supr
- Remove Links
- Set As
- Set As Categorical
- Set Column Values... Ctrl+Q
- Set Multiple Columns Values... Ctrl+Mayusculas+Q
- Fill Column with
- Set Sampling Interval...
- Show X Column...
- Filter
- Mask
- Mask Cells by Condition...
- Sort Column
- Sort Worksheet
- Sort Columns by Label...
- Reverse Order
- Normalize...
- Frequency Count...
- Statistics on Column
- Hide/Unhide Columns
- Move Columns
- Swap Columns...
- Column Width

- Line
- Symbol
- Line + Symbol
- Column/Bar/Pie
- Multi-Curve
- 3D XY
- 3D Surface
- 3D Symbol/Bar/Vector
- Statistics
- Area
- Contour
- Specialized
- Stock
- User Defined
- Template Library...
- 1 Histogram
- 2 Column
- 3 Scatter
- 4 Column + Label
- 5 Line + Symbol
- 6 Color Map Surface
- 7 3D Scatter



File Edit View Graph Data Analysis Gadgets Tools Format Window Help

100%

Default: Arial 0 B I U x² x αβ A

Book1

	A(X)	B(Y)
Long Name		
Units		
Comments		
F(x)		
9	2,3	
10	2,3	
11	2	
12	2,35	
13	2	
14	2,45	
15	2	
16	2	
17	2	
18		
19		

Sheet1

Graph2

Plot Details - Plot Properties

Graph2

- Layer1
 - [Book1]Sheet1! A(Y) [1*:17*]

Pattern Spacing Data

Type Dots

Single Block Barplot

Automatic Binning

Bin Size 0,1

Number of Bins 7

Begin 1,9

End 2,5

Bin Height (0-100) 100

Bin Worksheet

Add Distribution Curves

Go

Distribution Curve

Type None

Bins Alignment

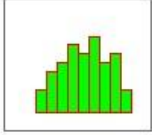
Center

Right

Left

Data Width (%) Auto

Preview



The Counts column in the Bin Worksheet can be used for fitting.

Plot Type: Histogram

>> Workbook OK Cancel Apply

Count

6

4

2

0

1,8

C

for Help, press F1

-- AU : ON Dark Colors & Light Grids 1:[Book1]Sheet1!Col(A)[1:17] 1:[Graph2]!11 Radian

ESP 11:31

Pagina "bins" pares x, y

X: longitud

Y: cuentas

Para buscar la mejor curva

Analysis => Fitting

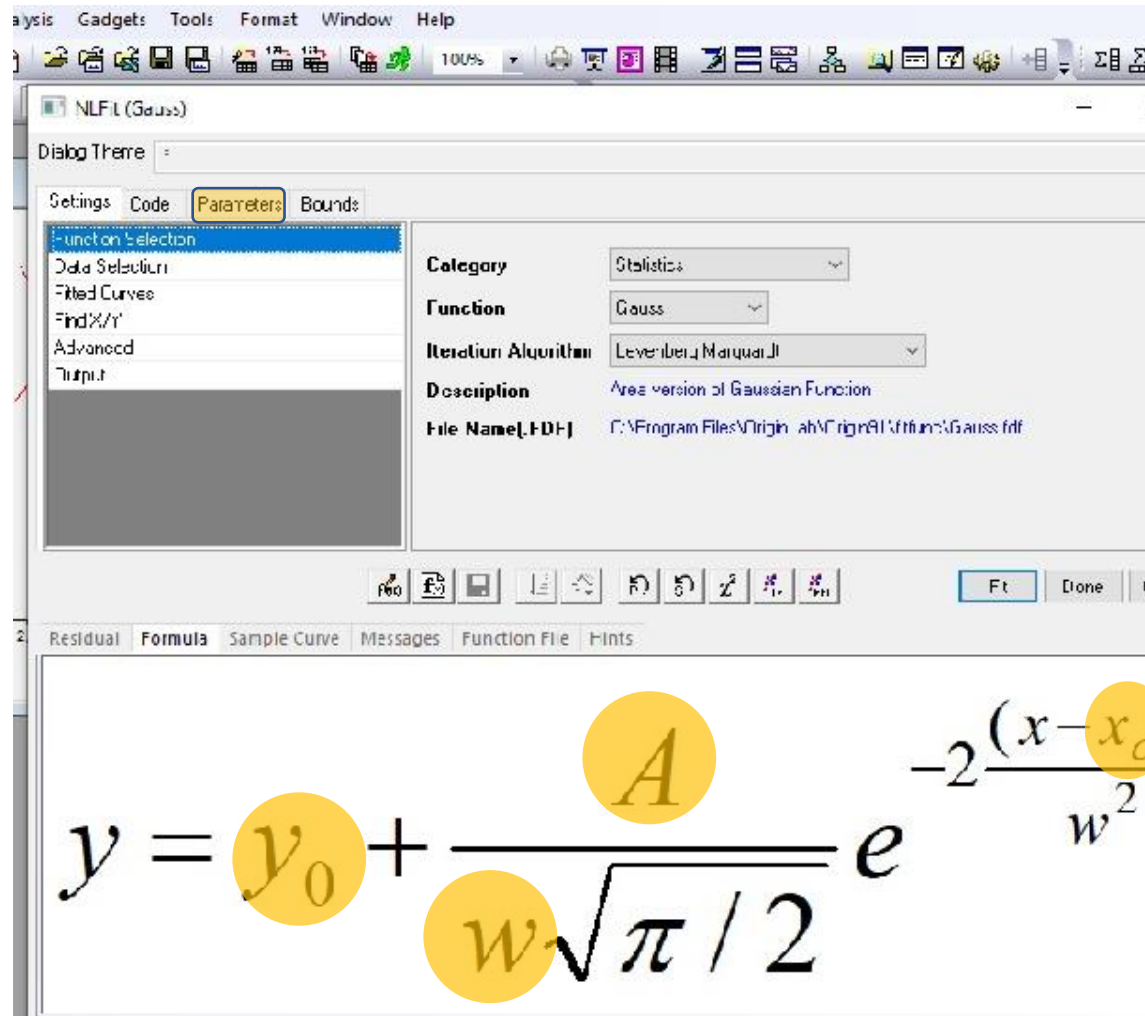
=> Nonlinear curve fit

=> Open dialog

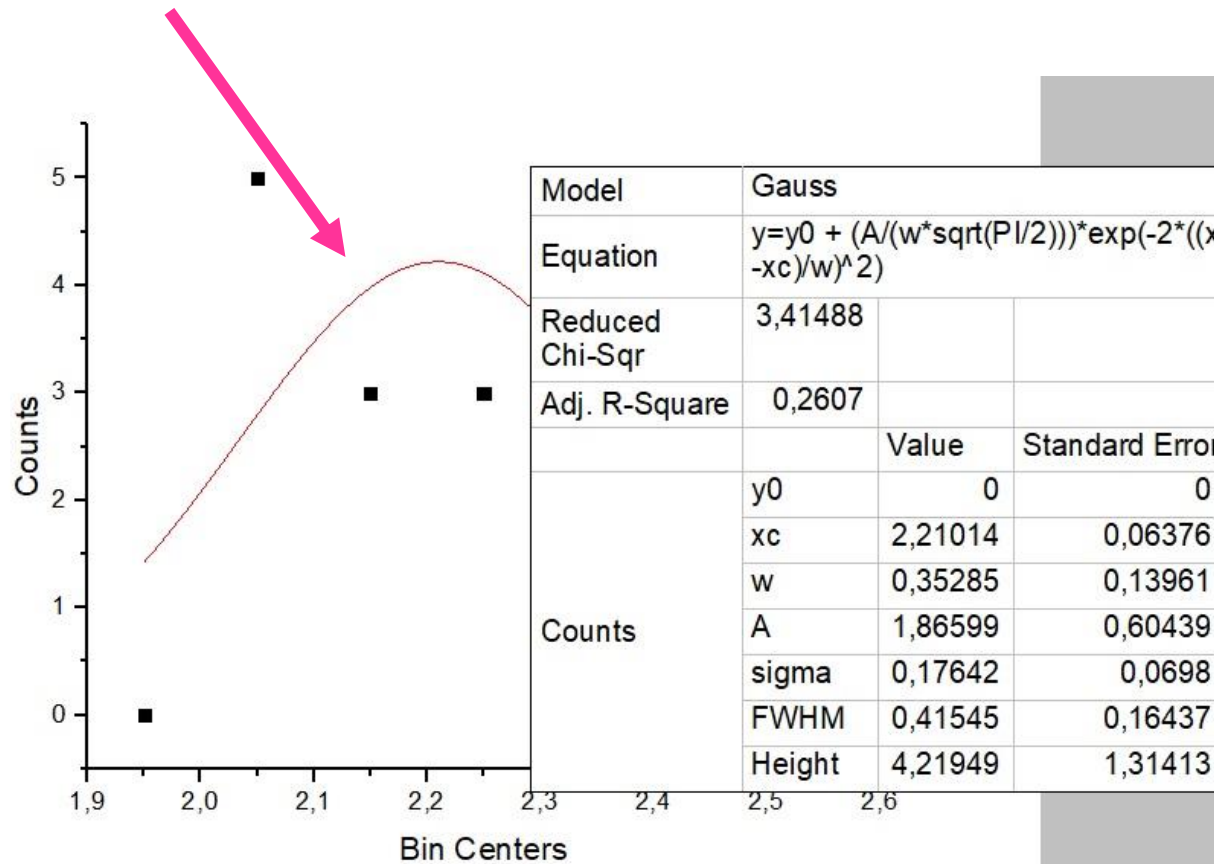
En la ventana elegir:

Category: Statistics

Function: Gauss



AJUSTE



Chi-Sqr
R-square
Standard error

INFORME

Informe

- Título
- Lista de autores
- Resumen
- Introducción teórica/ antecedentes problema
- Detalles Experimentales
- Resultados y discusión
 - Gráficos
 - Tablas
- Conclusiones
- Bibliografía/ Referencias

C:/Users/Laura/Desktop/Augusto/BIBLIOMAG/RotatableBarturenM-EPJB86-4-2013.pdf

Rotatable anisotropy of epitaxial $\text{Fe}_{1-x}\text{Ga}_x$ thin films*

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Abstract. We show by a combined magnetic force microscopy and synchrotron radiation spectroscopy study that stripe-like patterned magnetic domains are present in $\text{Fe}_{1-x}\text{Ga}_x$ thin films. These stripes, whose origin is attributed to an out-of-plane magnetic component, can be rotated by an external magnetic field.

1 Introduction

Coupling magnetization of nanostructures to external non-magnetic fields is a challenge of today's research on nanomagnetism. For instance, electric fields were added to control local magnetization in multiferroic materials [1], spin polarized currents to generate RF coherent emission in nanopillars [2], self-organized templates to switch magnetization [3]. These and many others experiments promise new means to control local magnetic properties in spintronics devices avoiding cumbersome inductive means.

In this context, magnetoelastic coupling in magnetostrictive nanomagnets has potential for controlling magnetic properties by mechanical deformation. For instance, some of us reported recently high-frequency (around 200 MHz) magnetocaloric effect triggering in MnAs thin films epitaxied on GaAs(001) substrates [4].

These considerations motivate the magnetic properties study reported in this article. We focus on strong magnetoelastic $\text{Fe}_{1-x}\text{Ga}_x$ thin films prepared by Molecular Beam Epitaxy on GaAs(001). It is well known that $\text{Fe}_{1-x}\text{Ga}_x$ magnetoelastic coupling is tuned by the Ga content, displaying a high λ_{100} coefficient (400×10^{-6} for $x = 20\%$) and a strong dependence of the magnetostrictive coefficient on the Ga concentration [5,6].

Here, we report on the rotatable anisotropy of

OP magnetic anisotropy due to $\text{Fe}_{1-x}\text{Ga}_x$ magnetostriction, probably enhanced by epitaxial constraints [7,8].

2 Sample growth

$\text{Fe}_{1-x}\text{Ga}_x$ thin films with $x = 15\%$ were deposited by MBE on $\text{C}(2 \times 2)$ -Zn terminated ZnSe epilayer, a prototype of low reactive iron/semiconductor interface [9]. Details of the MBE-growth of a pseudomorphic 20 nm thick ZnSe epilayer have been reported previously [7]. Such epilayer constitutes an efficient chemical barrier to separate $\text{Fe}_{1-x}\text{Ga}_x$ from the substrate. We kept constant the growth temperature at 180 °C. At the end of the Fe-Ga growth, the samples were transferred from the MBE chamber to UHV-interconnected multi-chambers, where films compositions were firstly analyzed by X-ray photoemission spectroscopy (XPS). At the end, the films were protected by a 3 nm thick gold capping layer.

3 Experimental

As observed in reference [7] $\text{Fe}_{1-x}\text{Ga}_x$ thin films are under a compressive strain. It was found that the in-plane lattice parameter of bulk iron is preserved leading to a marked tetragonal distortion. This tetragonal distortion is meta-

OJO

El informe va a una columna y espacio y medio de espaciado entre líneas.

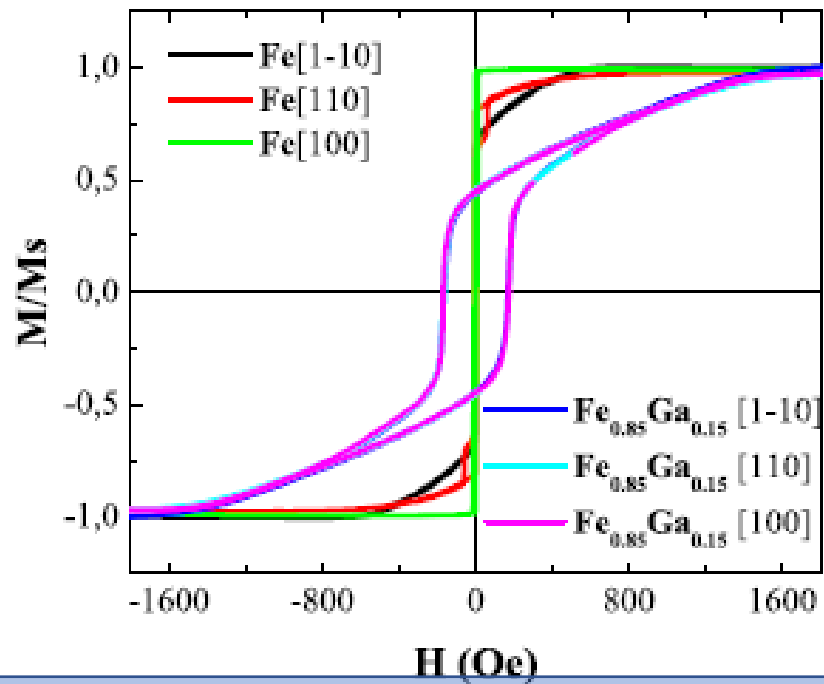


Fig. 2. VSM measurements of pure iron and FeGa thin films epitaxied on ZnSe/GaAs(001) substrates.